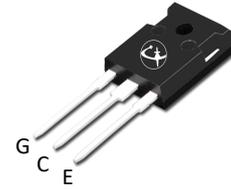
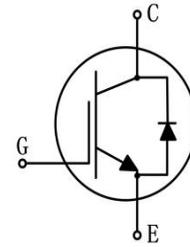


### MAIN CHARACTERISTICS

$I_C$ @TC=100°C	30A
$V_{CE}$	650V
$V_{CE(sat)}$ -typ	1.69V



TO-247

### FEATURES

- Positive temperature coefficient
- Fast Switching
- Low  $V_{CE(sat)}$
- Reliable and Rugged
- Halogen Free and Green Devices Available

### APPLICATIONS

- Motor drives
- Air Condition
- Inverters

### MECHANICAL DATA

- Case: Molded plastic
- Mounting Position: Any
- Molded Plastic: UL Flammability Classification Rating 94V-0
- Lead free in compliance with EU RoHS 2011/65/EU directive
- Solder bath temperature 275°C maximum, 10s per JESD 22-B106

### Product specification classification

Part Number	Package	Mode Name	Pack
LGT30N65HB	TO-247	LGT30N65HB	Tube

### Maximum Ratings

Parameter	Symbol	Value	Unit
Collector-emitter voltage	$V_{CES}$	650	V
Gate-emitter voltage	$V_{GES}$	$\pm 30$	V
Continuous collector current (TC=25°C)	$I_c$	60	A
Continuous collector current (TC=100°C)		30	A
Pulsed collector current, tp limited by Tvjmax	$I_{CM}$	90	A
Diode continuous forward current (TC=25°C)	$I_F$	60	A
Diode continuous forward current (TC=100°C)		30	A
Diode maximum current, tp limited by Tvjmax	$I_{FM}$	90	A
Power Dissipation @TC=25°C	PD	181	W
Operating junction temperature range	$T_{vj}$	-55 to +175	°C
Storage temperature range	$T_{stg}$	-55 to +175	°C

### Thermal characteristics

Parameter	Symbol	Values	Unit
Thermal resistance, junction to case for IGBT	$R_{th(j-c)}$	0.83	K/ W
Thermal resistance, junction to case for Diode	$R_{th(j-c)}$	0.65	K/ W
Thermal resistance, junction to ambient	$R_{th(j-a)}$	40	K/ W

Note1:Pulse test: 300  $\mu$ s pulse width, 2 % duty cycle

### Electrical characteristics of IGBT at $T_{vj}=25^\circ\text{C}$ unless otherwise specified

#### Static characteristics

Parameter	Test Condition	Symbol	Min	Typ	Max	Unit
Collector-emitter breakdown voltage	$V_{GE}=0V, I_c=250\mu A$	$BV_{CES}$	650	-	-	V
Collector-emitter leakage current	$V_{CE}=650V, V_{GE}=0V$	$I_{CES}$	-	-	10	$\mu A$
Gate leakage current, forward	$V_{GE}=\pm 20V, V_{CE}=0V$	$I_{GES}$	-	-	$\pm 200$	nA
Gate-emitter threshold voltage	$V_{GE}=V_{CE}, I_c=1mA$	$V_{GE(th)}$	4.3	5.3	6.3	V
Collector-emitter saturation voltage	$V_{GE}=15V, I_c=30A, T_{vj}=25^\circ\text{C}$	$V_{CE(sat)}$	-	1.69	2	V
	$V_{GE}=15V, I_c=30A, T_{vj}=125^\circ\text{C}$		-	1.9	-	V
	$V_{GE}=15V, I_c=30A, T_{vj}=175^\circ\text{C}$		-	2.05	-	V

#### Dynamic characteristics

Characteristics	Test Condition	Symbol	Min	Typ	Max	Unit
Input capacitance	$V_{CE}=25V$ $V_{GE}=0V$ $f=1MHz$	$C_{ies}$	-	1840	-	pF
Output capacitance		$C_{oes}$	-	111	-	pF
Reverse transfer capacitance		$C_{res}$	-	49	-	pF
Total gate charge	$V_{CC}=520V, V_{GE}=15V, I_c=30A$	$Q_g$	-	98	-	nC
Gate- Emitter Charge		$Q_{ge}$	-	18	-	nC
Gate- Collector Charge		$Q_{gc}$	-	47	-	nC
Short circuit collector current Max.1000 short circuits, times between short circuits: $\geq 1.0s$	$V_{GE}=15V, V_{CC}\leq 400V$ $T_J\leq 175^\circ\text{C}$	$t(SC)$	-	8	-	$\mu s$

### Electrical characteristics of IGBT at $T_{vj}=25^{\circ}\text{C}$ unless otherwise specified

#### Switching characteristics

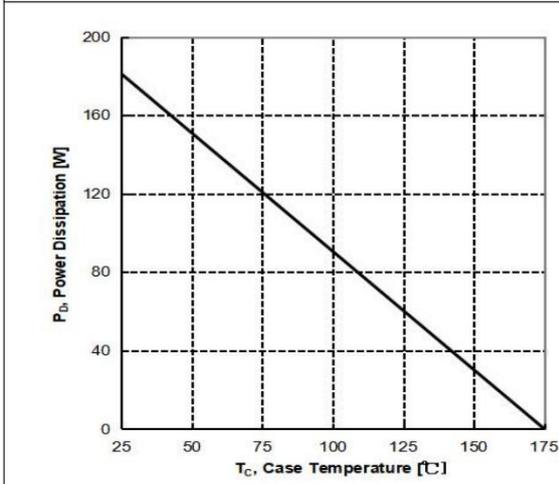
Characteristics	Test Condition	Symbol	Min	Typ	Max	Unit
Turn-on delay time	$V_{CC}=400\text{V}$ $V_{GE}=15\text{V}$ $I_C=30\text{A}$ $R_G=5\Omega$ Inductive load	td(on)	-	16	-	ns
Rise time		tr	-	46	-	ns
Turn-off delay time		td(off)	-	72	-	ns
Fall time		tf	-	80	-	ns
Turn-on energy		Eon	-	0.52	-	mJ
Turn-off energy		Eoff	-	0.77	-	mJ
Total switching energy		Ets	-	1.29	-	mJ
Turn-on delay time	$V_{CC}=400\text{V}$ $V_{GE}=15\text{V}$ $I_C=30\text{A}$ $R_G=5\Omega$ Inductive load $T_{vj}=175^{\circ}\text{C}$	td(on)	-	18	-	ns
Rise time		tr	-	54	-	ns
Turn-off delay time		td(off)	-	83	-	ns
Fall time		tf	-	75	-	ns
Turn-on energy		Eon	-	0.97	-	mJ
Turn-off energy		Eoff	-	1.36	-	mJ
Total switching energy		Ets	-	2.33	-	mJ

### Electrical characteristics of Diode at $T_{vj}=25^{\circ}\text{C}$ unless otherwise specified

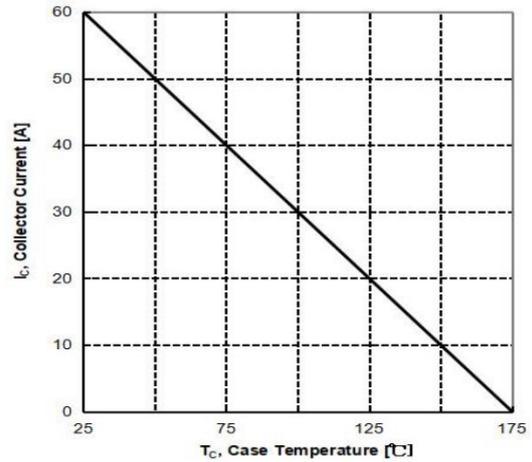
Characteristics	Test Condition	Symbol	Min	Typ	Max	Unit
Diode forward voltage	$I_F=30\text{A}$ $T_{vj}=25^{\circ}\text{C}$	VF	-	1.66	1.95	V
	$I_F=30\text{A}$ $T_{vj}=125^{\circ}\text{C}$		-	1.5	-	V
	$I_F=30\text{A}$ $T_{vj}=175^{\circ}\text{C}$		-	1.43	-	V
Diode reverse recovery time	$I_F=30\text{A}$ $diF/dt=-200\text{A}/\mu\text{s}$	trr	-	48	-	ns
Diode peak reverse recovery current		Qrr	-	80	-	nC
Diode reverse recovery charge		Irrm	-	5.1	-	A
Diode reverse recovery time	$I_F=30\text{A}$ $diF/dt=-200\text{A}/\mu\text{s}$ $T_{vj}=175^{\circ}\text{C}$	trr	-	39	-	ns
Diode peak reverse recovery current		Qrr	-	127	-	nC
Diode reverse recovery charge		Irrm	-	8.5	-	A

### RATINGS AND CHARACTERISTIC CURVES

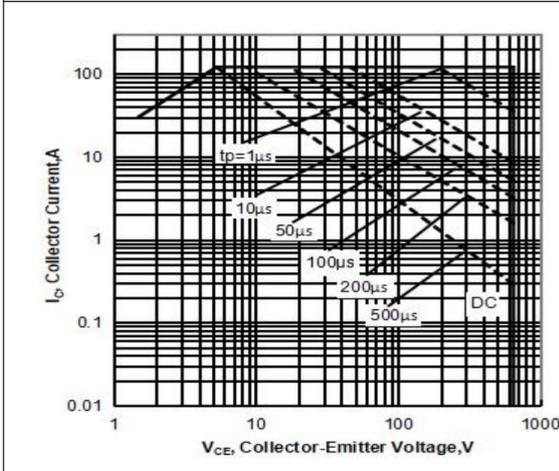
**Figure 1: Power Dissipation**



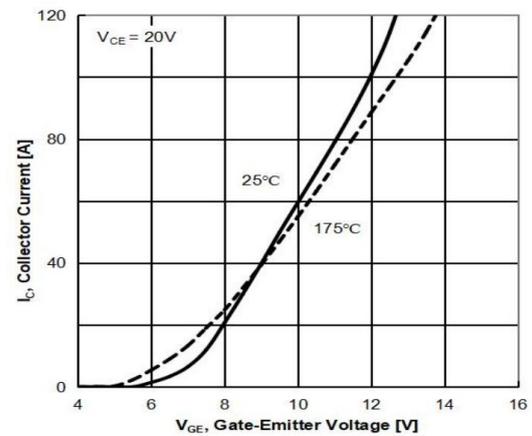
**Figure 2: Collector Current vs. Case Temperature**



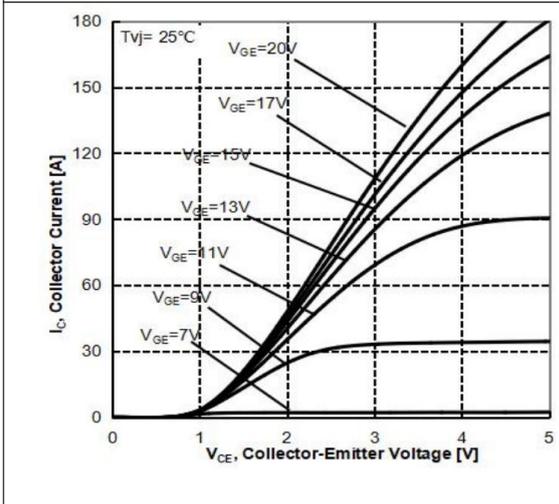
**Figure 3: Safe Operation Area**



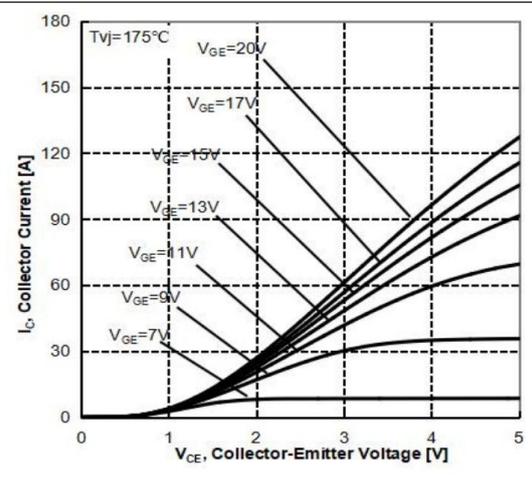
**Figure 4: Typical Transfer Characteristics**



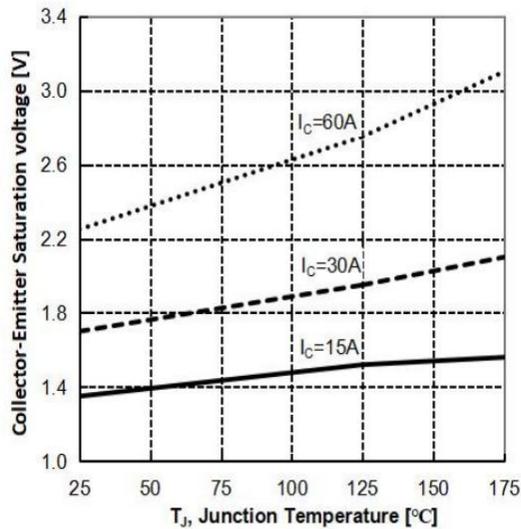
**Figure 5: Typical Output Characteristics**



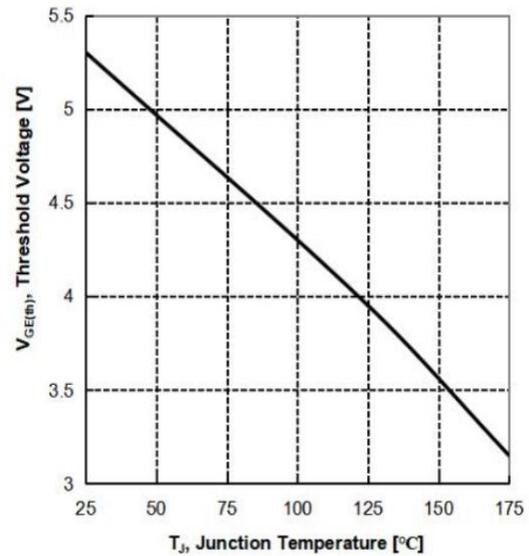
**Figure 6: Typical Output Characteristics**



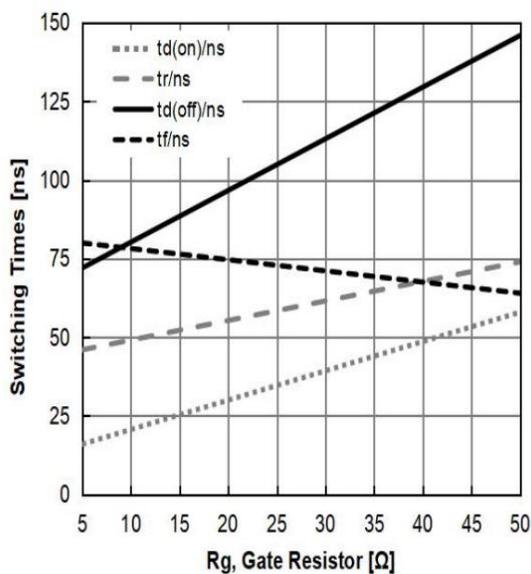
**Figure 7: Typical Collector-Emitter Saturation Voltage vs. Junction Temperature**



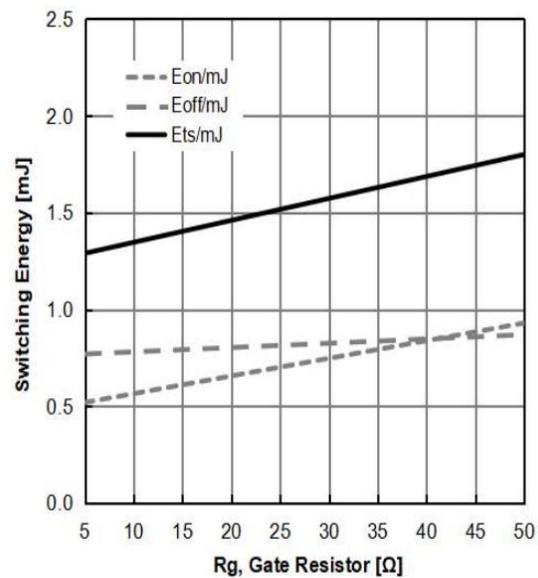
**Figure 8: Typical Gate-Emitter Threshold Voltage vs. Junction Temperature**



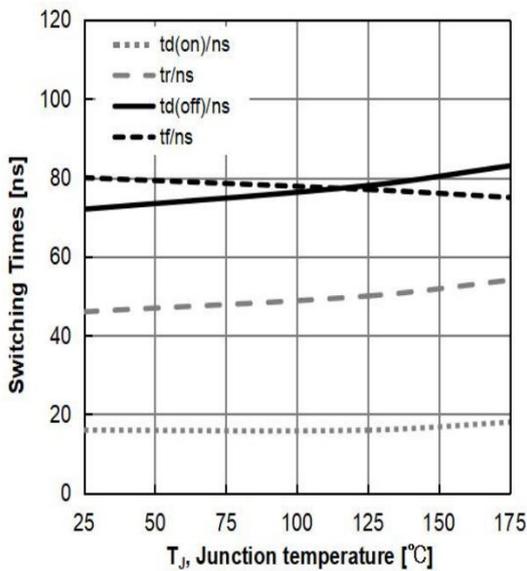
**Figure 9: Typical Switching Times vs. Gate Resistor (T<sub>J</sub>=25°C, V<sub>CE</sub>=400V, V<sub>GE</sub>=15/0V, I<sub>C</sub>=30A)**



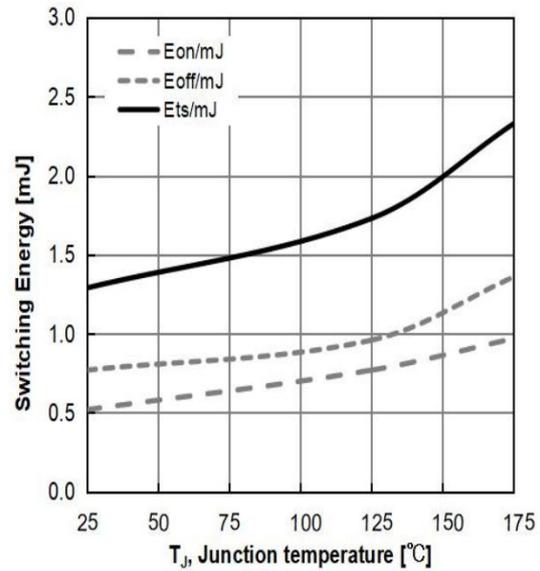
**Figure 10: Typical Switching Energy vs. Gate Resistor (T<sub>J</sub>=25°C, V<sub>CE</sub>=400V, V<sub>GE</sub>=15/0V, I<sub>C</sub>=30A)**



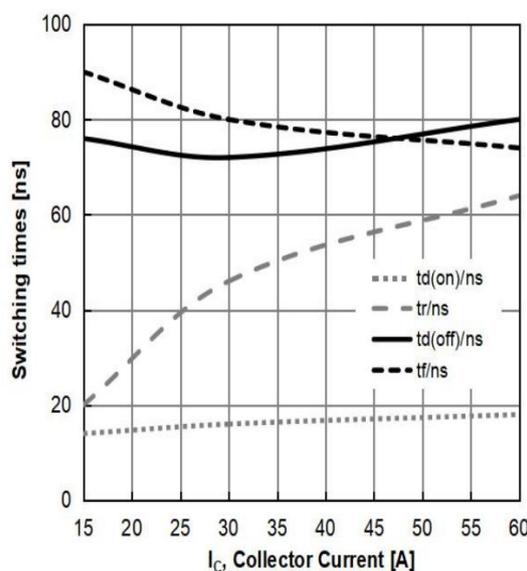
**Figure 11: Typical Switching Times vs. Junction Temperature ( $V_{CE}=400V$ ,  $V_{GE}=15/0V$ ,  $I_C=30A$ )**



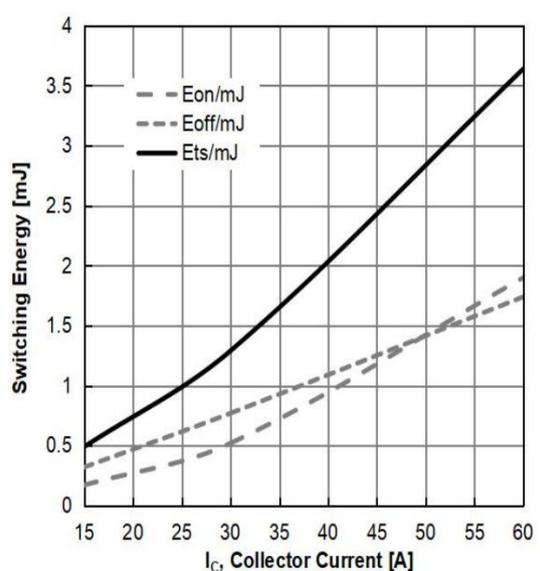
**Figure 12: Typical Switching Energy vs. Junction Temperature ( $V_{CE}=400V$ ,  $V_{GE}=15/0V$ ,  $I_C=30A$ )**



**Figure 13: Typical Switching Times vs. Collector Current ( $T_J=25^\circ C$ ,  $V_{CE}=400V$ ,  $V_{GE}=15/0V$ )**

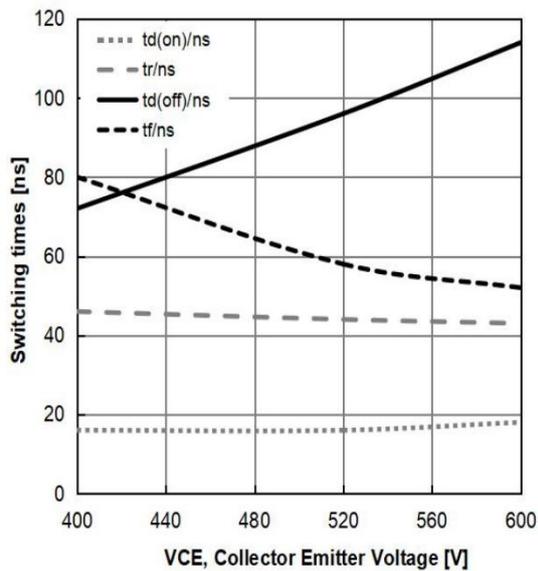


**Figure 14: Typical Switching Energy vs. Collector Current ( $T_J=25^\circ C$ ,  $V_{CE}=400V$ ,  $V_{GE}=15/0V$ )**

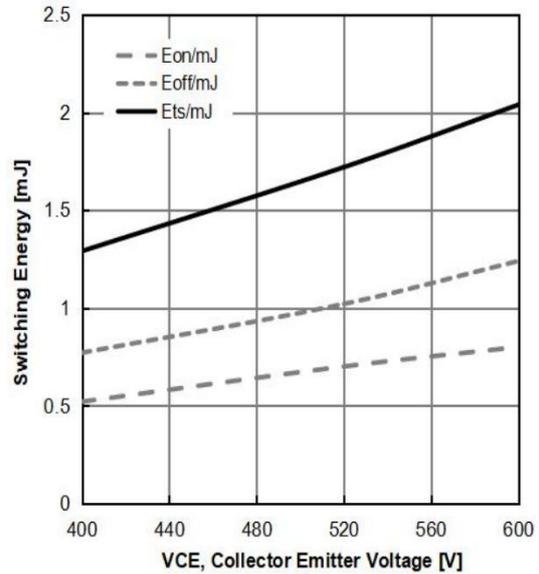


### RATINGS AND CHARACTERISTIC CURVES

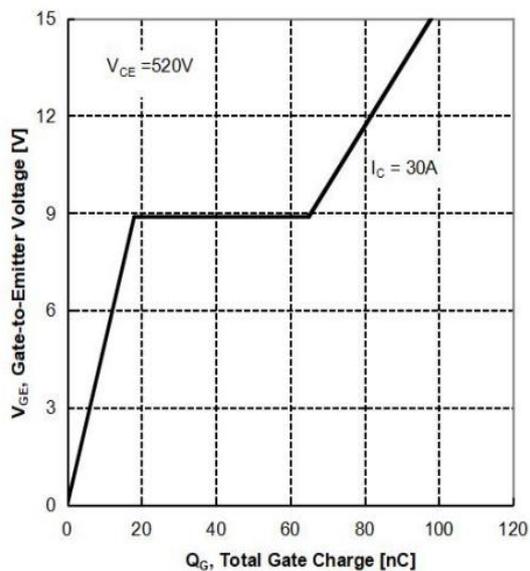
**Figure 15: Typical Switching Times vs. VCE (  $T_J=25^\circ\text{C}, V_{GE}=15/0\text{V}, I_C=30\text{A}$  )**



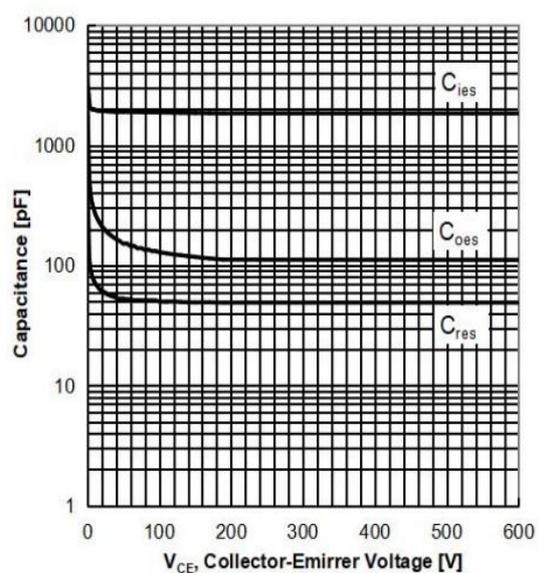
**Figure 16: Typical Switching Energy vs. VCE (  $T_J=25^\circ\text{C}, V_{GE}=15/0\text{V}, I_C=30\text{A}$  )**



**Figure 17: Typical Gate Charge**

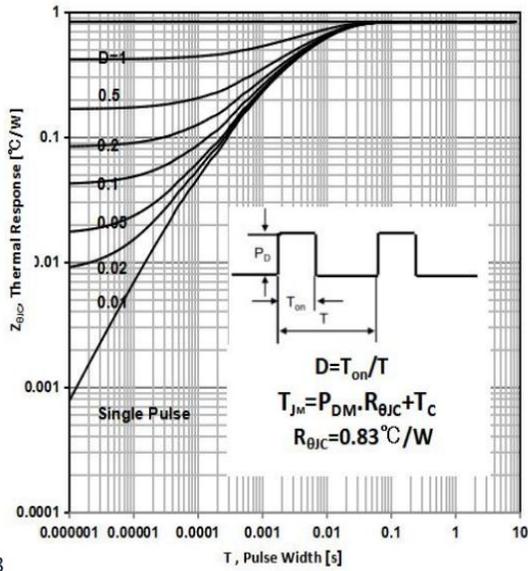


**Figure 18: Typical Capacitance vs. Collector-Emmitter Voltage**

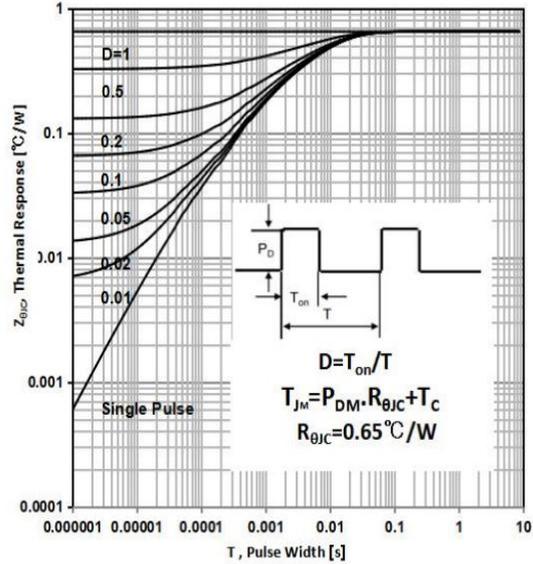


### RATINGS AND CHARACTERISTIC CURVES

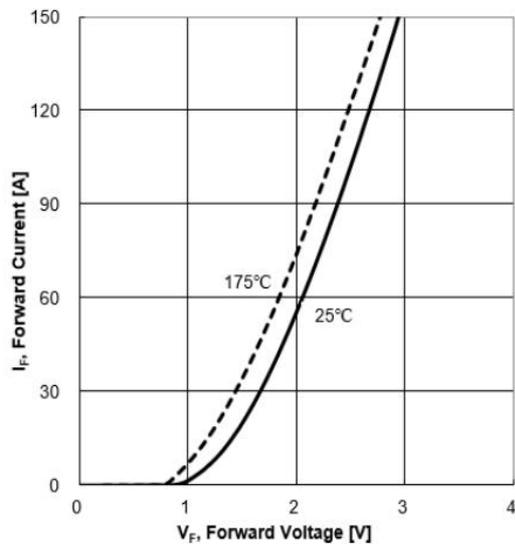
**Figure 19: IGBT Transient Thermal Impedance vs. Pulse Width**



**Figure 20: Diode Transient Thermal Impedance vs. Pulse Width**

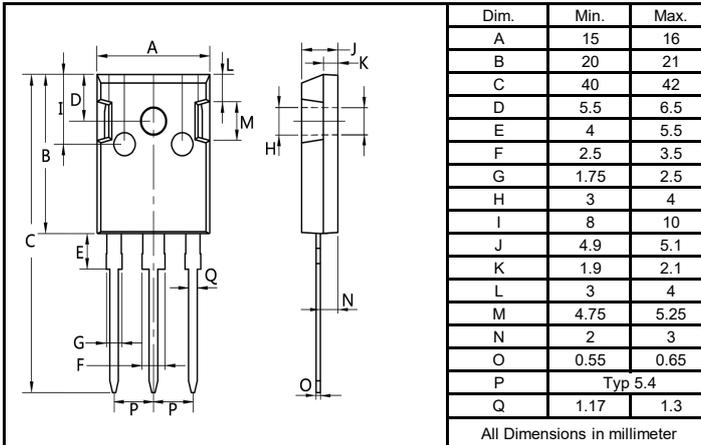


**Figure 21: Typical Diode Forward Current vs. Forward Voltage**

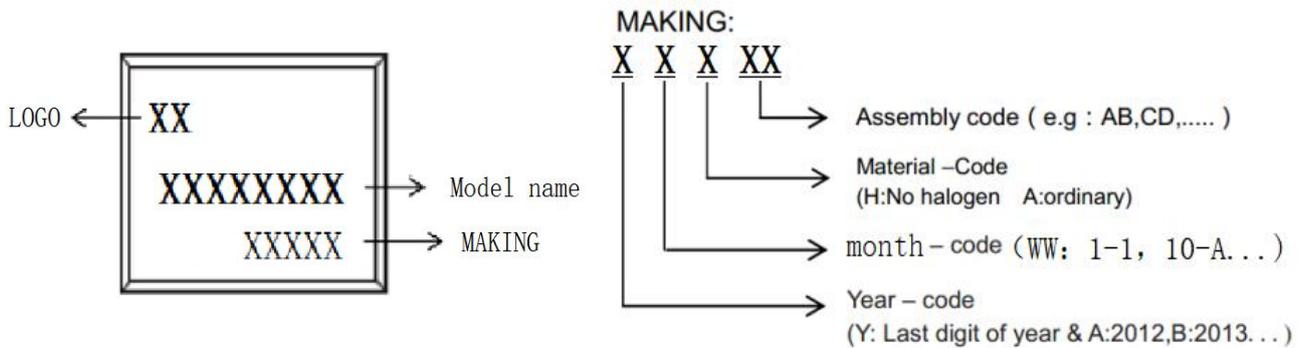


### Package Outline Dimensions millimeters

T0-247



### Marking on the body



### packing instruction

PKG	Minimal Package	Mini Box	Box
T0-247			
	30pcs/pdpe	600pcs/box	3000pcs/box



# LGT30N65HB

## N-Channel Enhancement Mode Power IGBT

### Notice

All product, product specifications and data are subject to change without notice to improve. The right to explain is owned by LINGXUN electronics company.

Confirm that operation temperature is within the specified range described in the product specification. Avoid applying power exceeding normal rated power; exceeding the power rating under steady-state loading condition may negatively affect product performance and reliability.

LINGXUN electronics shall not be in any way responsible or liable for failure induced under deviant condition from what is defined in this document.

<http://www.lxmicro.com>

### Revision History

Rev	Changes	Date
1.0	First version	2025-6-26